

Consortium Contact:
Bob Helsel
Semiconductor Test Consortium
303.652.1311
bhelsel@semitest.org

Agency Contact:
Ellen Van Etten
MCA
970.778.6094
evanetten@mcapr.com



SEMICONDUCTOR TEST CONSORTIUM ANNOUNCES GLOBAL STC CONFERENCE FOR 2008

“Collaborative Solutions Beyond 2010” Selected as Conference Theme

NIWOT, Colorado, April 29, 2008—The Semiconductor Test Consortium, Inc. (STC), the leading proponent of the development and adoption of value-added open test standards that benefit the semiconductor industry, today announced the dates for the annual Global STC Conference (GSC) and revealed this year’s theme of “Collaborative Solutions Beyond 2010”. This interactive global forum, open to both STC member and non-members, will be held on June 4th-6th in San Diego, California.

Incorporating feedback from the 2007 event and input from visionary industry leaders who will be presenting this year, the third annual GSC will focus on investigating collaborative solutions to address today’s most important test challenges. Participants from around the world will attend a wide-breadth of presentations hosted by luminaries representing leading companies and industry organizations, including those from integrated device manufacturers, electronic design automation firms, and outsourced semiconductor assembly and test companies. Face-to-face STC working group meetings will be scheduled before or after GSC, which are open to GSC attendees on the subjects of: docking and interface, portable test instrument module, probe card, yield enhancement analysis tools and university.

In a move reflective of this year’s theme around collaboration, the GSC has formed a conference partnership with the IEEE Semiconductor Wafer Test Workshop (SW Test) and the Design Automation Conference (DAC). Both conferences run the week following GSC and will, like GSC, focus on important challenges facing the global semiconductor industry.

"The IEEE Semiconductor Wafer Test Workshop is pleased to support, promote, and collaborate with the Global STC Conference," stated Dr. Jerry Broz, SW Test-2008 General Chair. "This synergistic relationship reflects the overall trends in the consumer environment in which highly demanding technical requirements for cost effective test are being aggressively pursued in both probe and tester technologies. Technical exchange and participant interaction at such international conferences and workshops is a vital element in the pursuit of optimal wafer sort."

"I want to thank SW Test and DAC for their support, and of course all of the industry leaders who will be attending and have agreed to present at GSC," said Risto Puhakka, President, VLSI Research Inc. "Collaborative solutions seemed the perfect theme for this year. The test challenges we face are indeed more than any one company could address on its own. But because of STC and events, like GSC, the semiconductor industry is today realizing success through collaboration. The fact is this very event is a testament to both the merits of collaboration and the semiconductor industry’s commitment to realize success through open partnerships."

The Global STC Conference will be held in the Hilton Hotel in San Diego Mission Valley, and will kickoff with a keynote speech by Puhakka after registration and lunch. Online registration is already available for those interested in attending. For more information please visit:

http://www.semitest.org/events/GSC_2008/.

About the Semiconductor Test Consortium

The Semiconductor Test Consortium (STC) was founded in 2003. Open to all companies throughout the semiconductor supply chain with a vested interest in the test sector, the consortium is focused on the following goals: formalizing a broadened STC scope with new working groups and specification structure; fostering pre-competitive collaboration among industry participants toward development of value-added standards; emphasizing the value of work being accomplished and the contributions to the industry; and continuing efforts to fully enable the STC Ecosystem, through its OPENSTAR[®] and STIX[™] initiatives. Today, 35 semiconductor, equipment and instrumentation companies worldwide, 41 university members in Europe, Japan, China and the United States, and 11 individuals support the STC. More information can be found at www.semitest.org.

###

STIX and OPENSTAR are trademarks or registered trademarks of the Semiconductor Test Consortium.